

IRG4PF50WDPbF

INSULATED GATE BIPOLAR TRANSISTOR WITH
ULTRAFAST SOFT RECOVERY DIODE

Features

- Optimized for use in Welding and Switch-Mode Power Supply applications
- Industry benchmark switching losses improve efficiency of all power supply topologies
- 50% reduction of Eoff parameter
- Low IGBT conduction losses
- Latest technology IGBT design offers tighter parameter distribution coupled with exceptional reliability
- IGBT co-packaged with HEXFRED™ ultrafast, ultra-soft-recovery anti-parallel diodes for use in bridge configurations
- Industry standard TO-247AC package
 - Lead-Free

Benefits

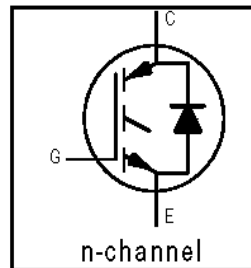
- Lower switching losses allow more cost-effective operation and hence efficient replacement of larger-die MOSFETs up to 100kHz
- HEXFRED™ diodes optimized for performance with IGBTs. Minimized recovery characteristics reduce noise, EMI and switching losses

Absolute Maximum Ratings

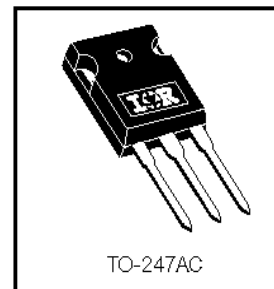
| | Parameter | Max. | Units |
|---------------------------------|--|------------------------------------|-------|
| V_{CES} | Collector-to-Emitter Breakdown Voltage | 900 | V |
| $I_C @ T_C = 25^\circ\text{C}$ | Continuous Collector Current | 51 | A |
| $I_C @ T_C = 100^\circ\text{C}$ | Continuous Collector Current | 28 | |
| I_{CM} | Pulsed Collector Current ① | 204 | |
| I_{LM} | Clamped Inductive Load Current ② | 204 | |
| $I_F @ T_C = 100^\circ\text{C}$ | Diode Continuous Forward Current | 16 | |
| I_{FM} | Diode Maximum Forward Current | 204 | |
| V_{GE} | Gate-to-Emitter Voltage | ± 20 | V |
| $P_D @ T_C = 25^\circ\text{C}$ | Maximum Power Dissipation | 200 | W |
| $P_D @ T_C = 100^\circ\text{C}$ | Maximum Power Dissipation | 78 | |
| T_J | Operating Junction and | -55 to + 150 | °C |
| T_{STG} | Storage Temperature Range | | |
| | Soldering Temperature, for 10 seconds | 300 (0.063 in. (1.6mm) from case) | |
| | Mounting torque, 6-32 or M3 screw. | 10 lbf·in (1.1N·m) | |

Thermal Resistance

| | Parameter | Min. | Typ. | Max. | Units |
|-----------------|---|------|----------|------|--------|
| $R_{\theta JC}$ | Junction-to-Case - IGBT | — | — | 0.64 | °C/W |
| $R_{\theta JC}$ | Junction-to-Case - Diode | — | — | 0.83 | |
| $R_{\theta CS}$ | Case-to-Sink, flat, greased surface | — | 0.24 | — | |
| $R_{\theta JA}$ | Junction-to-Ambient, typical socket mount | — | — | 40 | |
| Wt | Weight | — | 6 (0.21) | — | g (oz) |



| |
|---|
| $V_{CES} = 900\text{V}$ |
| $V_{CE(on)} \text{ typ.} = 2.25\text{V}$ |
| @ $V_{GE} = 15\text{V}, I_C = 28\text{A}$ |



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Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

| | Parameter | Min. | Typ. | Max. | Units | Conditions |
|---------------------------------|---|------|-------|-----------|---------|---|
| $V_{(BR)CES}$ | Collector-to-Emitter Breakdown Voltage ^③ | 900 | — | — | V | $V_{GE} = 0V, I_C = 250\mu A$ |
| $\Delta V_{(BR)CES}/\Delta T_J$ | Temperature Coeff. of Breakdown Voltage | — | 0.295 | — | V/°C | $V_{GE} = 0V, I_C = 3.5mA$ |
| $V_{CE(on)}$ | Collector-to-Emitter Saturation Voltage | — | 2.25 | 2.7 | V | $I_C = 28A, V_{GE} = 15V$ |
| | | — | 2.74 | — | | $I_C = 60A$ See Fig. 2, 5 |
| | | — | 2.12 | — | | $I_C = 28A, T_J = 150^\circ\text{C}$ |
| $V_{GE(th)}$ | Gate Threshold Voltage | 3.0 | — | 6.0 | | $V_{CE} = V_{GE}, I_C = 250\mu A$ |
| $\Delta V_{GE(th)}/\Delta T_J$ | Temperature Coeff. of Threshold Voltage | — | -13 | — | mV/°C | $V_{CE} = V_{GE}, I_C = 250\mu A$ |
| g_{fe} | Forward Transconductance ^④ | 26 | 39 | — | S | $V_{CE} = 50V, I_C = 28A$ |
| I_{CES} | Zero Gate Voltage Collector Current | — | — | 500 | μA | $V_{GE} = 0V, V_{CE} = 900V$ |
| | | — | — | 2.0 | | $V_{GE} = 0V, V_{CE} = 10V, T_J = 25^\circ\text{C}$ |
| | | — | — | 6.5 | mA | $V_{GE} = 0V, V_{CE} = 900V, T_J = 150^\circ\text{C}$ |
| V_{FM} | Diode Forward Voltage Drop | — | 2.5 | 3.5 | V | $I_C = 16A$ See Fig. 13 |
| | | — | 2.1 | 3.0 | | $I_C = 16A, T_J = 150^\circ\text{C}$ |
| I_{GES} | Gate-to-Emitter Leakage Current | — | — | ± 100 | nA | $V_{GE} = \pm 20V$ |

Switching Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

| | Parameter | Min. | Typ. | Max. | Units | Conditions |
|------------------|--|------|------|------|------------|--|
| Q_g | Total Gate Charge (turn-on) | — | 160 | 240 | nC | $I_C = 28A, V_{CC} = 400V$ See Fig. 8 $V_{GE} = 15V$ |
| Q_{ge} | Gate - Emitter Charge (turn-on) | — | 19 | 29 | | |
| Q_{gc} | Gate - Collector Charge (turn-on) | — | 53 | 80 | | |
| $t_{d(on)}$ | Turn-On Delay Time | — | 71 | — | ns | $T_J = 25^\circ\text{C}$ $I_C = 28A, V_{CC} = 720V$ $V_{GE} = 15V, R_G = 5.0\Omega$ Energy losses include "tail" and diode reverse recovery. |
| t_r | Rise Time | — | 50 | — | | |
| $t_{d(off)}$ | Turn-Off Delay Time | — | 150 | 220 | | |
| t_f | Fall Time | — | 110 | 170 | | See Fig. 9, 10, 18 |
| E_{on} | Turn-On Switching Loss | — | 2.63 | — | mJ | |
| E_{off} | Turn-Off Switching Loss | — | 1.34 | — | | |
| E_{ts} | Total Switching Loss | — | 3.97 | 5.3 | | |
| $t_{d(on)}$ | Turn-On Delay Time | — | 69 | — | ns | $T_J = 150^\circ\text{C}$, See Fig. 11, 18 $I_C = 28A, V_{CC} = 720V$ $V_{GE} = 15V, R_G = 5.0\Omega$ Energy losses include "tail" and diode reverse recovery. |
| t_r | Rise Time | — | 52 | — | | |
| $t_{d(off)}$ | Turn-Off Delay Time | — | 270 | — | | |
| t_f | Fall Time | — | 190 | — | | |
| E_{ts} | Total Switching Loss | — | 6.0 | — | mJ | |
| L_E | Internal Emitter Inductance | — | 13 | — | nH | Measured 5mm from package |
| C_{ies} | Input Capacitance | — | 3300 | — | pF | $V_{GE} = 0V, V_{CC} = 30V$ See Fig. 7 $f = 1.0MHz$ |
| C_{oes} | Output Capacitance | — | 200 | — | | |
| C_{res} | Reverse Transfer Capacitance | — | 45 | — | | |
| t_{rr} | Diode Reverse Recovery Time | — | 90 | 135 | ns | $T_J = 25^\circ\text{C}$ See Fig. 14 $T_J = 125^\circ\text{C}$ 14 |
| | | — | 164 | 245 | | |
| I_{rr} | Diode Peak Reverse Recovery Current | — | 5.8 | 10 | A | $T_J = 25^\circ\text{C}$ See Fig. 15 $T_J = 125^\circ\text{C}$ 15 |
| | | — | 8.3 | 15 | | |
| Q_{rr} | Diode Reverse Recovery Charge | — | 260 | 675 | nC | $T_J = 25^\circ\text{C}$ See Fig. 16 $T_J = 125^\circ\text{C}$ 16 |
| | | — | 680 | 1838 | | |
| $di_{(rec)M}/dt$ | Diode Peak Rate of Fall of Recovery During t_b | — | 120 | — | A/ μs | $T_J = 25^\circ\text{C}$ See Fig. 17 $T_J = 125^\circ\text{C}$ 17 |
| | | — | 76 | — | | |

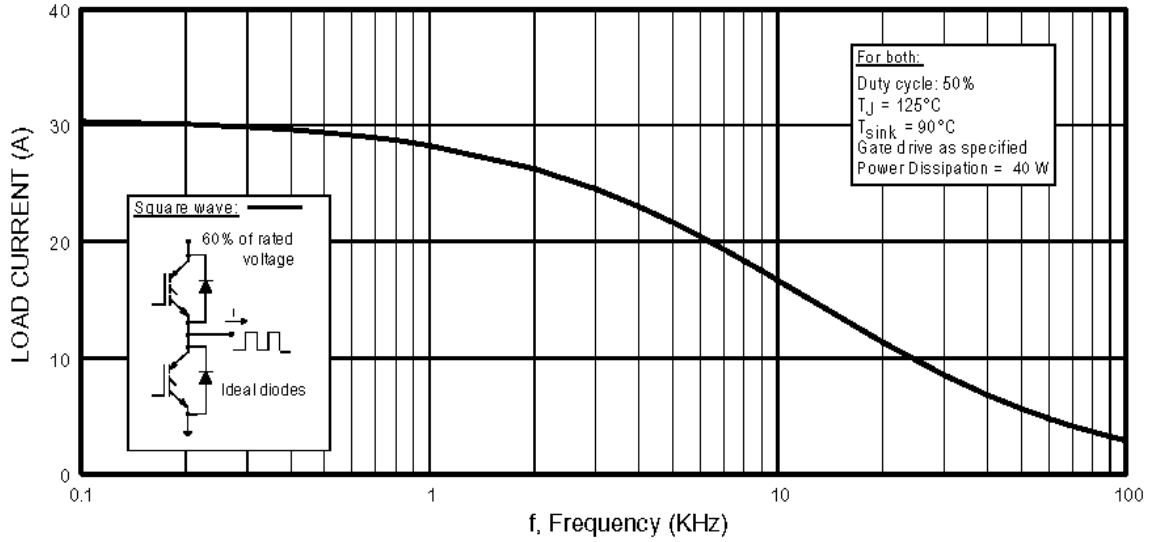


Fig. 1 - Typical Load Current vs. Frequency
 (Load Current = I_{RMS} of fundamental)

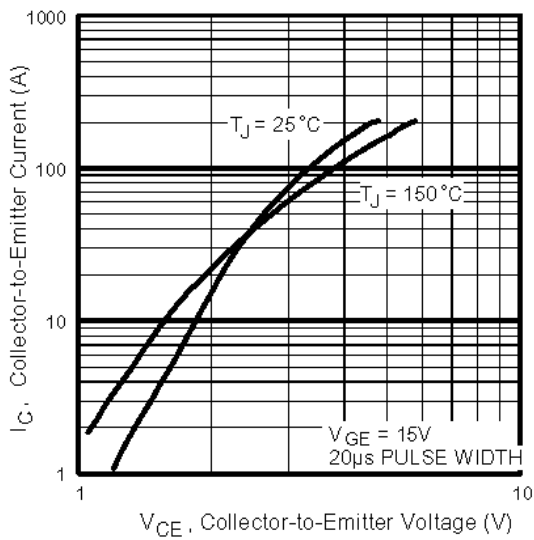


Fig. 2 - Typical Output Characteristics
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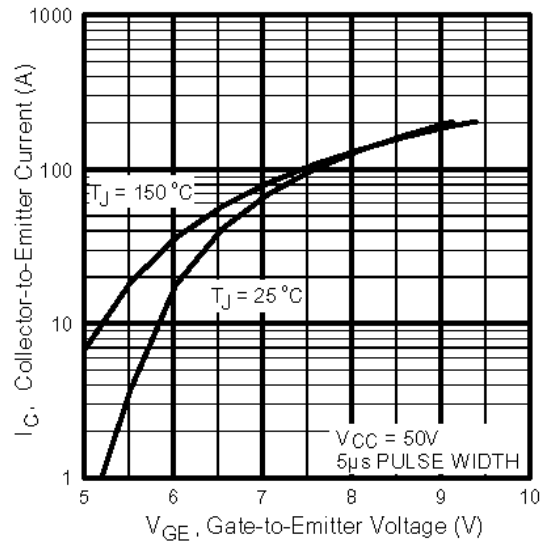


Fig. 3 - Typical Transfer Characteristics

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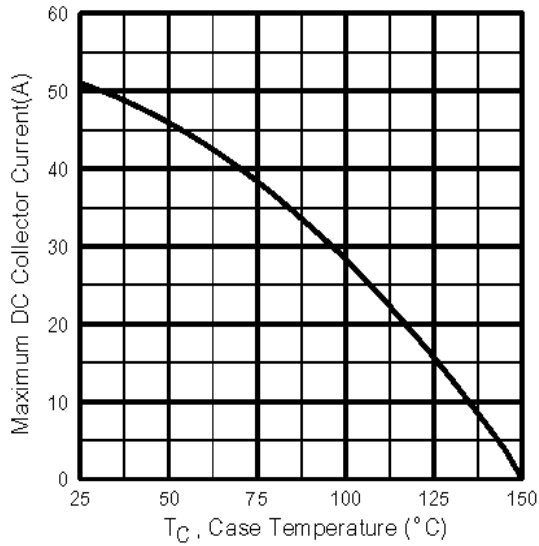


Fig. 4 - Maximum Collector Current vs. Case Temperature

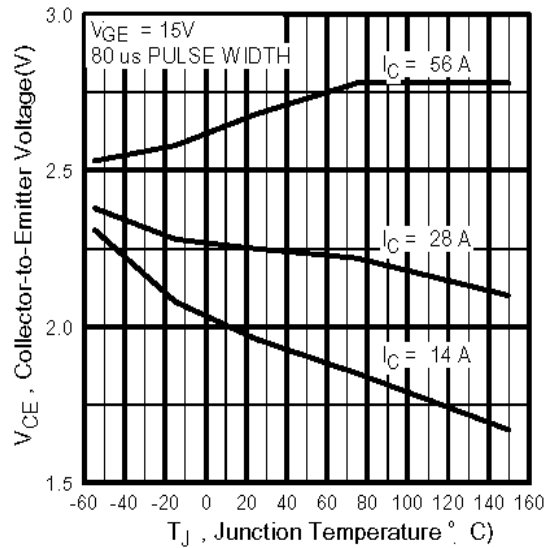


Fig. 5 - Collector-to-Emitter Voltage vs. Junction Temperature

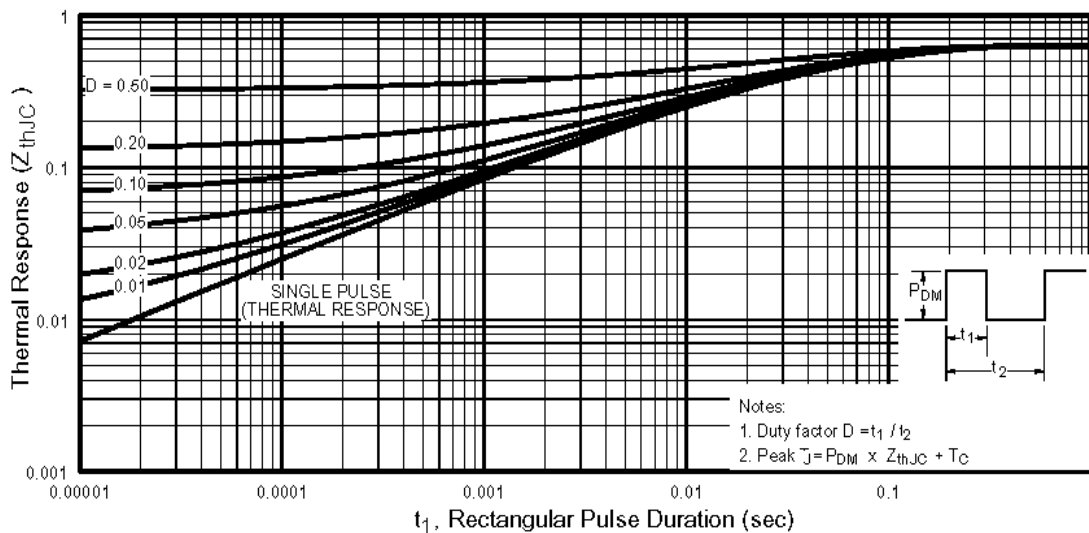


Fig. 6 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

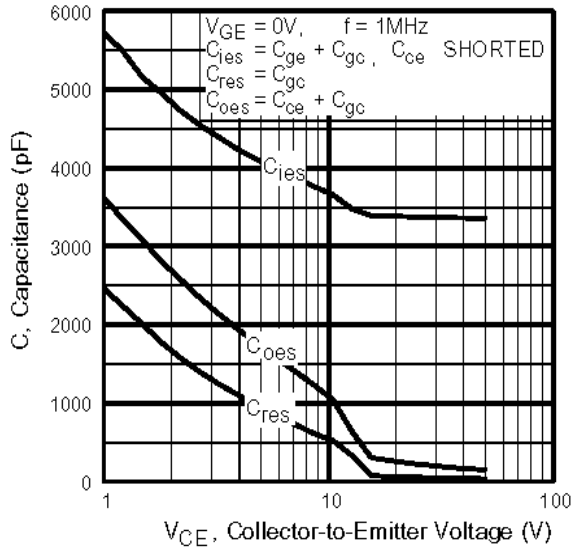


Fig. 7 - Typical Capacitance vs. Collector-to-Emitter Voltage

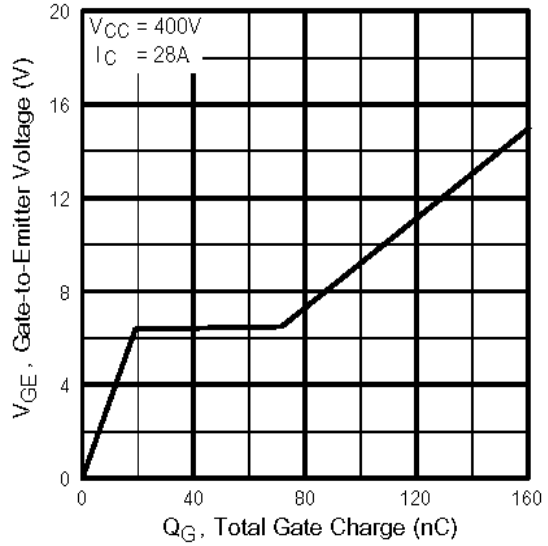


Fig. 8 - Typical Gate Charge vs. Gate-to-Emitter Voltage

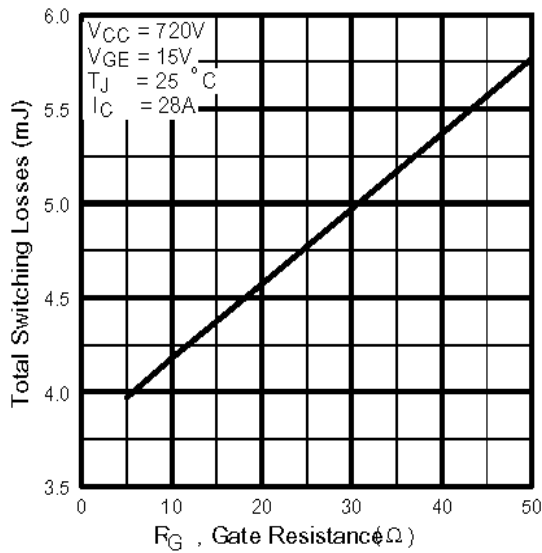


Fig. 9 - Typical Switching Losses vs. Gate Resistance

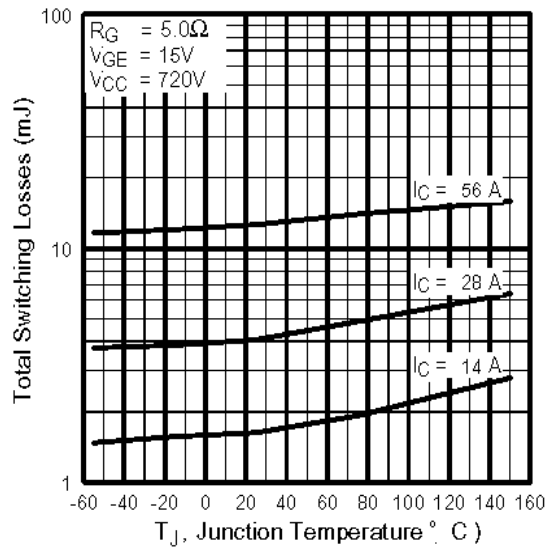


Fig. 10 - Typical Switching Losses vs. Junction Temperature

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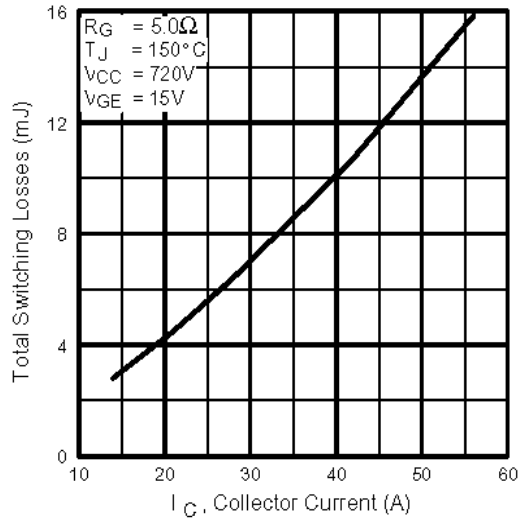


Fig. 11 - Typical Switching Losses vs. Collector-to-Emitter Current

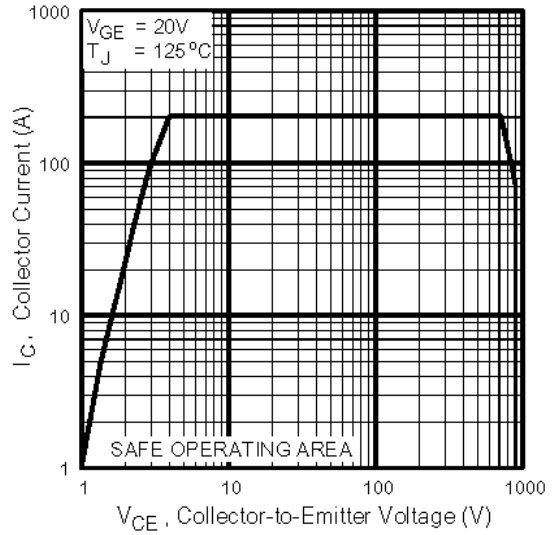


Fig. 12 - Turn-Off SOA

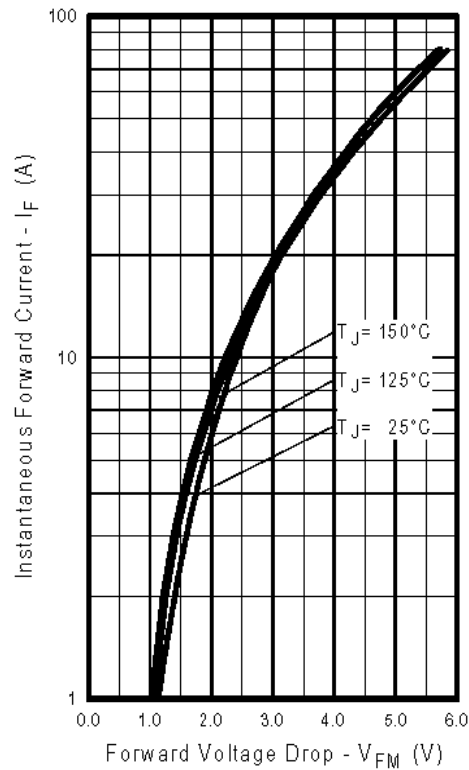


Fig. 13 - Typical Forward Voltage Drop vs. Instantaneous Forward Current

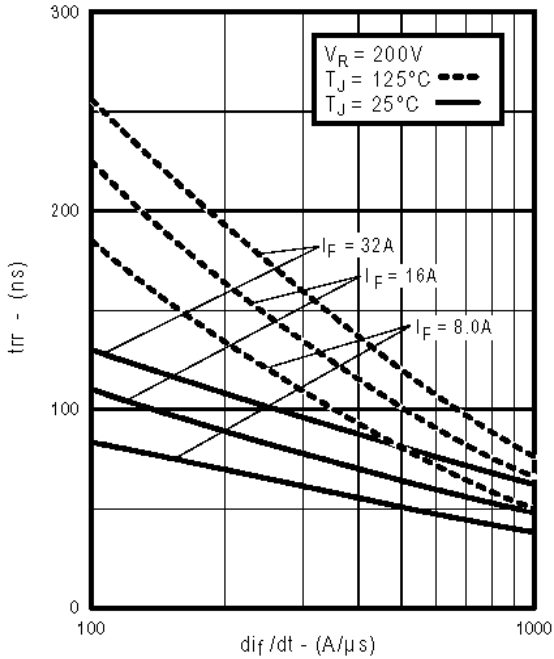


Fig. 14 - Typical Reverse Recovery vs. di_f/dt

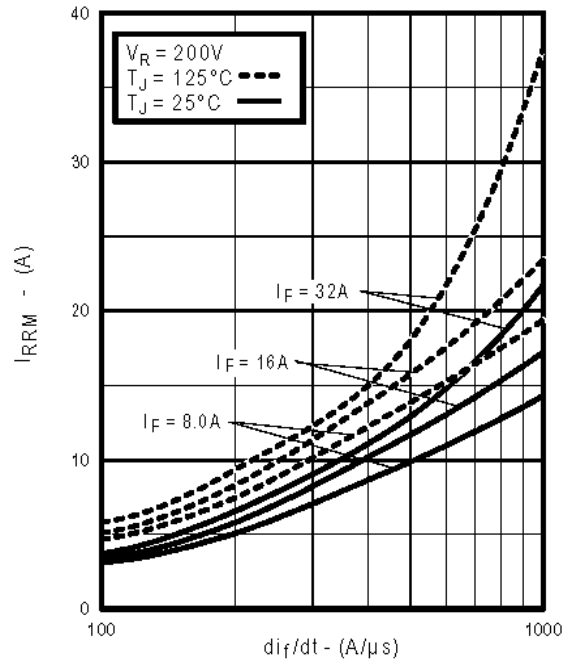


Fig. 15 - Typical Recovery Current vs. di_f/dt

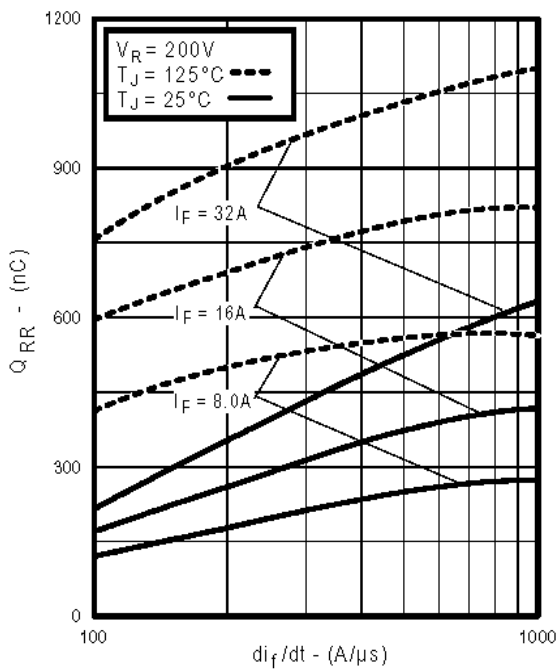


Fig. 16 - Typical Stored Charge vs. di_f/dt
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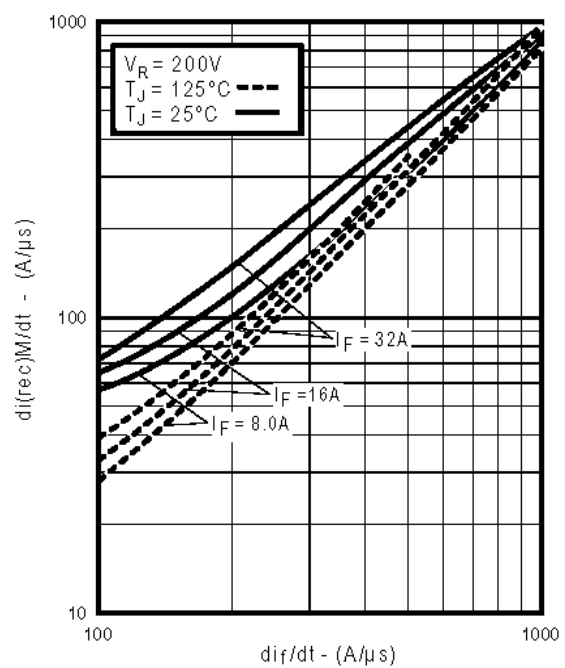


Fig. 17 - Typical $di_{(rec)M}/dt$ vs. di_f/dt

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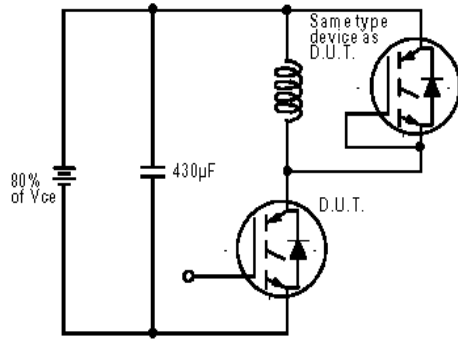


Fig. 18a - Test Circuit for Measurement of I_{LM} , E_{on} , $E_{off}(\text{diode})$, t_{rr} , Q_{rr} , I_{rr} , $t_{d(on)}$, t_r , $t_{d(off)}$, t_f

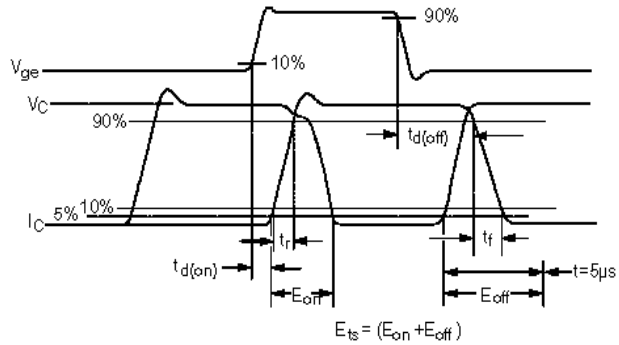


Fig. 18b - Test Waveforms for Circuit of Fig. 18a, Defining E_{off} , $t_{d(off)}$, t_f

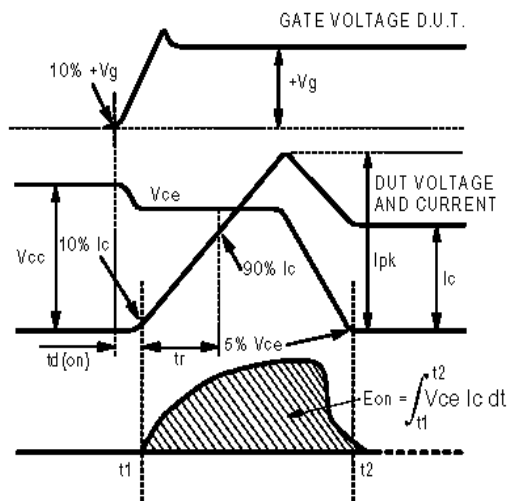


Fig. 18c - Test Waveforms for Circuit of Fig. 18a, Defining E_{on} , $t_{d(on)}$, t_r

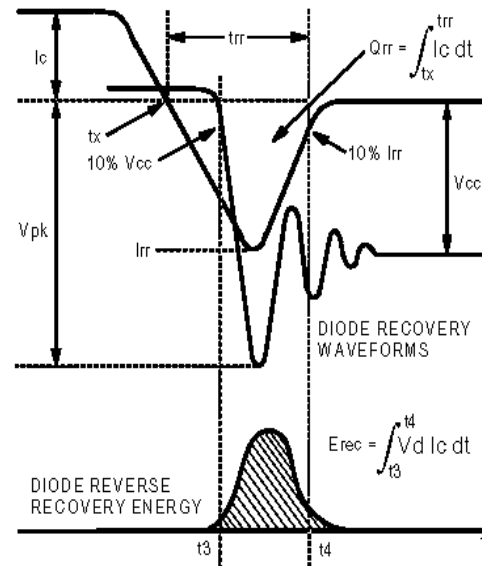


Fig. 18d - Test Waveforms for Circuit of Fig. 18a, Defining E_{rec} , t_{rr} , Q_{rr} , I_{rr}

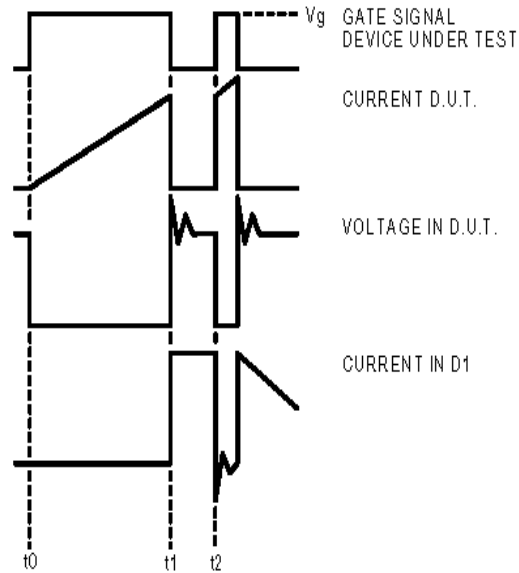


Figure 18e. Macro Waveforms for Figure 18a's Test Circuit

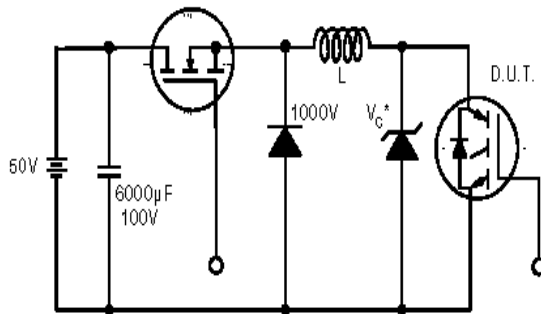


Figure 19. Clamped Inductive Load Test Circuit

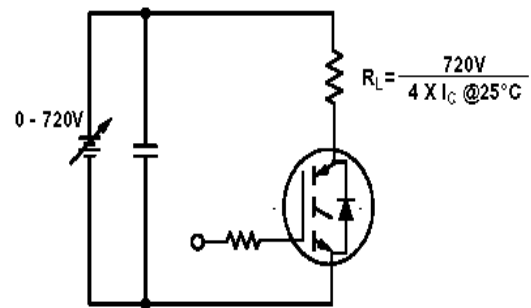


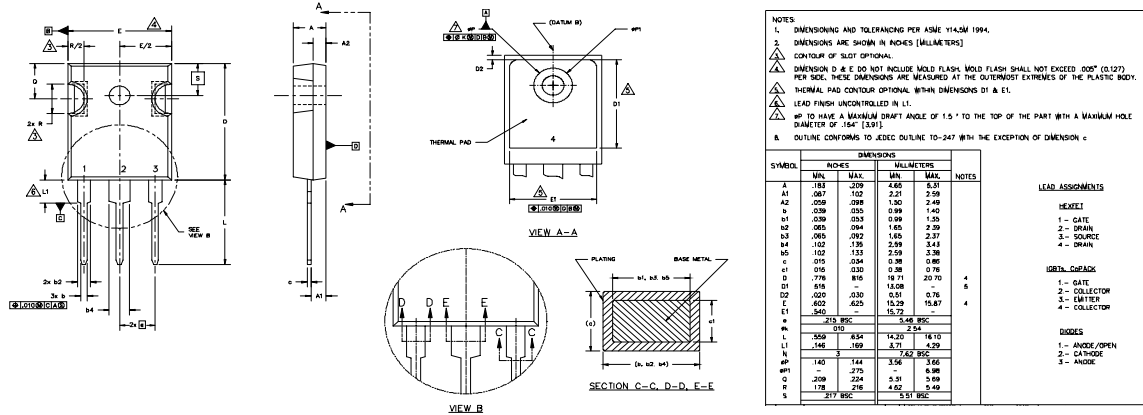
Figure 20. Pulsed Collector Current Test Circuit

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TO-247AC Package Outline

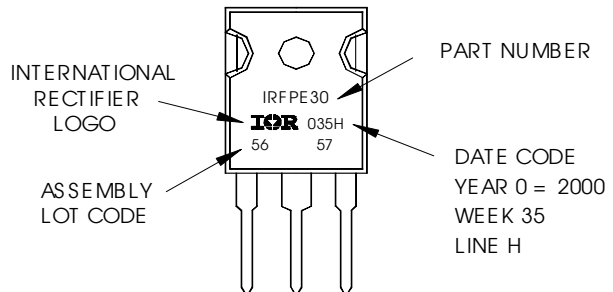
Dimensions are shown in millimeters (inches)



TO-247AC Part Marking Information

EXAMPLE: THIS IS AN IRFPE30
WITH ASSEMBLY
LOT CODE 5657
ASSEMBLED ON WW 35, 2000
IN THE ASSEMBLY LINE "H"

Note: "P" in assembly line position indicates "Lead-Free"



Data and specifications subject to change without notice.

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